

Docket No. 240486US2S

**IN RE APPLICATION OF: Yoshiyuki TANAKA**

SERIAL NO: 10/621.451

FILED: July 18, 2003

**FOR: NONVOLATILE SEMICONDUCTOR MEMORY**

**COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313**

SIR:

Transmitted herewith is an amendment in the above-identified application.

- No additional fee is required
  - Small entity status of this application under 37 C.F.R. §1.9 and §1.27 is claimed.
  - Additional documents filed herewith:

The Fee has been calculated as shown below:

- A check in the amount of \$0.00 is attached.
  - Credit card payment form is attached to cover the fees in the amount of \$0.00
  - Please charge any additional Fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.
  - If these papers are not considered timely filed by the Patent and Trademark Office, then a petition is hereby made under 37 C.F.R. §1.136, and any additional fees required under 37 C.F.R. §1.136 for any necessary extension of time may be charged to Deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.

OBLON, SPIVAK, McCLELLAND,  
MAIER & NEUSTADT, P.C.

Eckhard H. Kuesters

Registration No. 28,870

## Customer Number

22850

Tel. (703) 413-3000  
Fax. (703) 413-2220  
(OSMMN 05/03)



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IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF

YOSHIYUKI TANAKA

: EXAMINER: NGUYEN, HIEN N.

SERIAL NO: 10/621,451

:

FILED: JULY 18, 2003

: GROUP ART UNIT: 2824

FOR: NONVOLATILE  
SEMICONDUCTOR MEMORY

:

AMENDMENT

COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action dated March 4, 2005, please amend the above-identified application as follows:

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 3 of this paper.

**Remarks/Arguments** begin on page 15 of this paper.